PERFORMANCE CHECKSHEET

Model: AVR-CD1-B-AANB-SQMELF
Type: Semiconductor Device Tester
S.N.: 12180
Date: April 14, 2009

Output Amplitude: +0.1 to +10 A
Pulse Width (FWHM): 2 us
Switching Time, + to -: 100 – 200 A/us
PRF: 1 - 100 Hz
Jitter, Stability: OK
Prime Power: 100-240V AC, 50-60 Hz.

Test Waveforms

With an On Semi 1N4937 installed in the AVX-CD1-AANB daughterboard, +10A, 200 A/us.

Measured t<sub>RR</sub> = 90 ns.

With a Microsemi MQ1N5811US installed in the AVX-CD1-SQMELF daughterboard, +2A, 100 A/us.

Measured t<sub>RR</sub> = 31.6 ns.

More actual test results are provided in the “Typical Results” section of the manual.